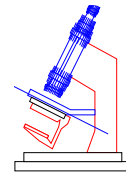


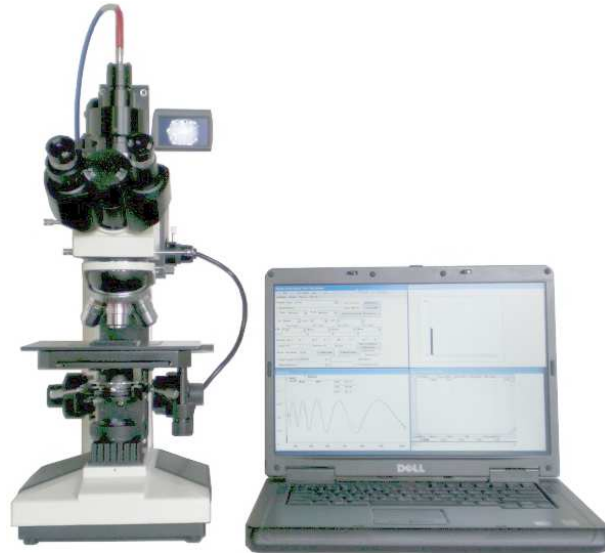
Mission Peak Optics Inc.



Microspot Thin Film Measurement System MP100-ME

Easy to use + Low Cost + Compact Size + Flexibility = High Performance

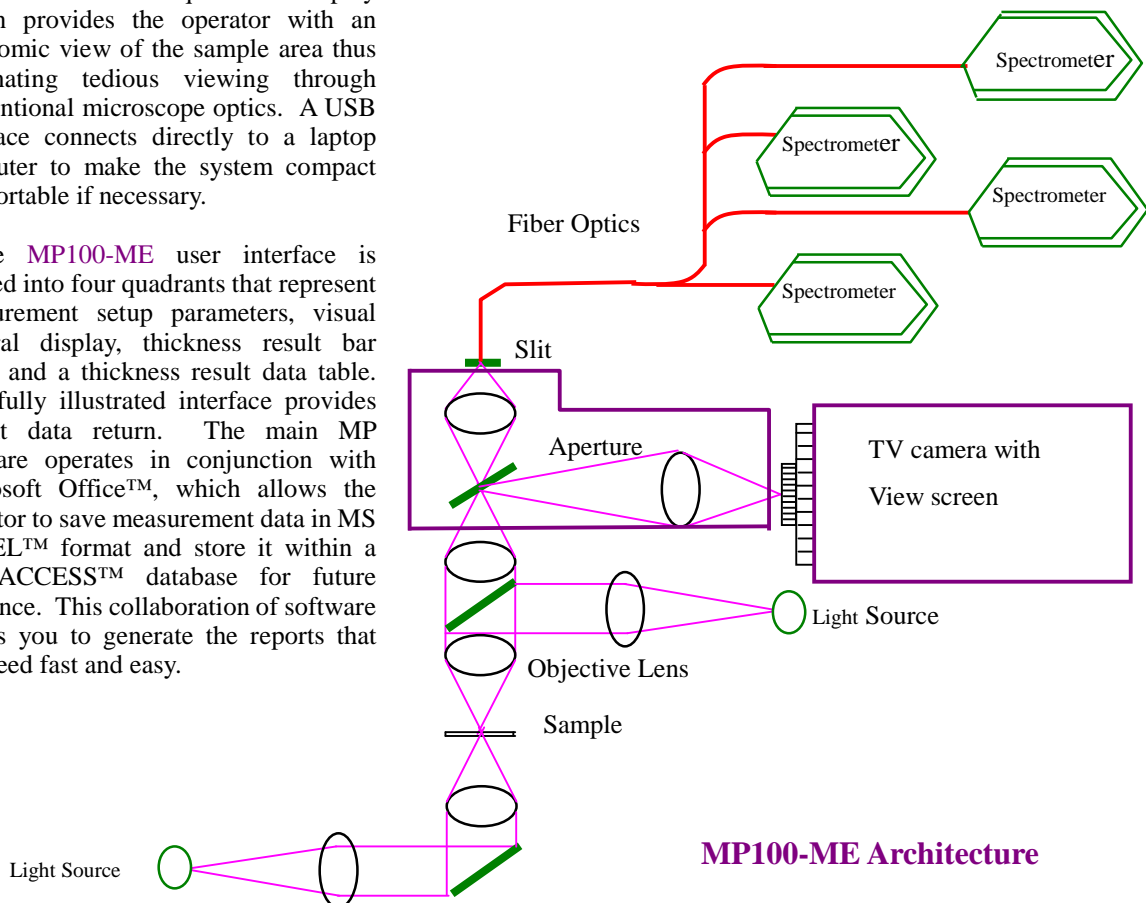
The **MP100-ME** Thin Film Measurement System comes standard with a manual microscope, which is designed to fit your application needs. The MP100-ME provides state-of-the-art function to measure filled cell gap on LCD, polyimide on ITO, color filter CIE chromaticity, and color filter thickness. MP100-ME is also able to measure Oxide, Nitride, Photoresist and Polysilicon films. The powerful software algorithms can perform single, double, and triple layer thickness calculations. As well as special search and fit routines that quickly converge the algorithm and variables into an accurate thickness measurement tool.



The **MP100-ME** uses multiple gratings to achieve a wide spectrum range from UV to NIR. The unique video display design provides the operator with an ergonomic view of the sample area thus eliminating tedious viewing through conventional microscope optics. A USB interface connects directly to a laptop computer to make the system compact and portable if necessary.

The **MP100-ME** user interface is divided into four quadrants that represent measurement setup parameters, visual spectral display, thickness result bar graph and a thickness result data table. This fully illustrated interface provides instant data return. The main MP software operates in conjunction with Microsoft Office™, which allows the operator to save measurement data in MS EXCEL™ format and store it within a MS ACCESS™ database for future reference. This collaboration of software allows you to generate the reports that you need fast and easy.

MP100-ME Microspot Thin Film Measurement System



MP100-ME Architecture

Specifications (MP100-ME):

Scanning range: 365 nm to 850 nm, standard
 Optional range: It is optional to choose different gratings for different ranges of scanning, such as: 200-575, 250-800, 530-1000, 200-450, the combination of the range can add up the range from 200 nm to 1000 nm.

Spectrum resolution: 2 nm
 Precision: 0.1 nm
 Measuring speed: 2 seconds

Measurement specification:

		1 st Layer		2 nd Layer		3 rd Layer		4 th Layer	
Film Type	Objective Lens	Range	1 σ	Range	1 σ	Range	1 σ	Range	1 σ
P1/P2/ITO/Oxide/Gla	5x, 10x	100 - 30,000Å	5Å	100 - 10,000Å	5Å	100 - 2,000Å	3Å	100 - 3,000Å	3Å
Oxide/Si	5x, 10x	200 - 30,000Å	2Å						
		30,000 - 50,000Å	5Å						
	40x, 60x	200 - 10,000Å	2Å						
		10,000 - 20,000Å	5Å						
Nitride/Si	5x, 10x	150 - 20,000Å	2Å						
	40x, 60x	150 - 15,000Å	2Å						
Photoresist/Si	5x, 10x, 40x	500 - 20,000Å	5Å						
Nitride/Oxide/Si	5x, 10x	150 - 20,000Å	5Å	100 - 10,000Å	5Å				
Poly/Oxide/Si	5x, 10x	100 - 5,000Å	5Å	100 - 10,000Å	5Å				
Oxide/Poly/Oxide/Si	5x, 10x	100 - 10,000Å	5Å	0 - 10,000Å	5Å	0 - 10,000Å	5Å		
Oxide/Al	5x, 10x, 40x	2,000 - 20,000Å	5Å						
Photoresist/Cr	5x, 10x, 40x	500 - 20,000Å	5Å						
Oxide/NiFe	5x, 10x, 40x	2,000 - 20,000Å	5Å						
Photoresist/Glass	5x, 10x, 40x	500 - 20,000Å	10Å						
ITO/Oxide/Glass	5x, 10x, 40x	100 - 3,000Å	2Å	100 - 2,000Å	2Å				
CIE Color measurement	5x								
Very Thick Film	5x	50,000-150,000Å	100Å						
Customized film types are available for your applications.									

Measuring spot size: 5x Objective is 50 microns, 10x Objective is 25 microns, 40x Objective is 7 microns, 60 Objective is 5 microns. Sample view: 3" video view screen and Trinocular, with Transmission mode

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